

Figure S.1. XRD data for $A=\mathrm{Na}^{+}$as prepared and after treatment with concentrated nitric acid. a) Data from $10-60^{\circ}$, inset shows the (110) reflection, b) the (100) reflection, $\mathbf{c}$ ) the (111) reflection, $\mathbf{d}$ ) the (200) reflection, and $\mathbf{e}$ ) the (211) reflection.


Figure S.2. SHG efficiency as a function of particle size for $A=\mathrm{K}^{+}$.
Table S.1. Space group, $R_{\text {wp }}, \chi^{2}$, and $A$-site $\mathrm{B}_{\mathrm{eq}}$ for Rietveld refinements on $A=\mathrm{K}^{+}$. Results shown for $P 4 m m, A m m 2$, and $R 3 m$ have been refined without constraints on the atomic positions of $A$-site cations.

| Space Group | $\boldsymbol{R}_{\mathbf{w p}}$ | $\chi^{2}$ | $\mathbf{B}_{\mathrm{eq}}{ }^{\dagger}$ |
| :--- | :---: | :---: | :--- |
| $P m \overline{3} m$ | 7.44 | 3.14 | $10.51(9)$ |
| $P 4 m m$ | 6.86 | 2.72 | $10.73(3)$ |
| $A m m 2$ | 6.81 | 2.63 | $10.70(2)$ |
| $R 3 m$ | 6.96 | 2.74 | $10.70(4)$ |
| $P m \overline{3} m[100]$ | 7.05 | 2.82 | $4.58(5)$ |
| + |  |  |  |

[^0]

Figure S.3. Results of combined Rietveld refinement on $A=\mathrm{K}^{+}$using synchrotron XRD and NPD data for a) $P m \overline{3} m$, b) $P 4 m m$, c) $A m m 2$, d) $R 3 m$, and e) [100] distorted $P m \overline{3} m$.


Figure S.4. Results of combined Rietveld refinement on $A=\mathrm{Na}^{+}$using synchrotron XRD and NPD data for a) $P 4 / \mathrm{mbm}$, b) Cmcm, c) $P b n m, ~ d) ~ P b c m$, and e) $R 3 c$, and f) $P 2_{1} / \mathrm{m}$.


Figure S.5. The fits of selected peaks for Rietveld refinement of XRD data for $A=\mathrm{Na}^{+}$in a) $P 4 / \mathrm{mbm}, \mathbf{b}$ ) $C m c m$, c) $P b n m, ~ d) ~ P b c m$, and e) $R 3 c$, and f) $P 2_{1} / m$ symmetry.


Figure S.6. Fourier difference map calculated from the Rietveld refinement of $A=\mathrm{Na}^{+}$in $P 4 / \mathrm{mbm}$, with a split oxygen site, on NPD data


[^0]:    $\dagger$ isotropic displacement parameter of the $A$-site Cation

